

We help designers and manufacturers

- Reduce design cycle time
- Minimize customer product returns
- Maximize product yields

Failure Analysis — Materials Analysis — Reliability Testing — Teardown Analysis

Welcome to our Newsletter

Paper presented this year so far:

Purple plague makes a comeback.

M. Simard-Normandin, C. Banks.
Presented at the 2019 SMTA ICEET Conference in Markham ON.
Full text available on demand.

Upcoming presentations:

ToF-SIMS, Time-of-Flight Secondary Ion Mass Spectroscopy for counterfeit detection of Electrical, Electronic, and Electromechanical (EEE) parts.

M. Simard-Normandin, C. Banks, N. Havercroft, P. Clark, E. Tallarek.

To be presented at ISTFA 2019, November 10-14, Portland OR.

<https://www.asminternational.org/web/istfa-2019/technical>

Upcoming courses:

Failure Analysis of Electronic Devices. Nov 9, morning

Shining a Light on LED Technology: Construction, Reliability, Qualification, Failure Modes, Nov 9, afternoon.

<https://www.asminternational.org/web/istfa-2019/education>

These courses are also offered on-demand at the Grafoid Global Technology Centre (GGTC), at **MuAnalysis**, or at your facility.
Contact us to arrange.

Equipment upgrades:

MuAnalysis has upgraded its EDX capability to a window-less Bruker detector.

MuAnalysis now offers access to its new EMI chamber.



The interior of the chamber is approximately 2ftx2ft.



MuAnalysis is an authorized distributor of the Hitachi Fine SAT V acoustic tomograph. Come try it.